

<b>Notice of References Cited</b>	Application/Control No. 10/601,275	Applicant(s)/Patent Under Reexamination YE ET AL.	
	Examiner Dah-Wei D. Yuan	Art Unit 1745	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0091891	05-2003	Yoshida et al.	429/44
*	B	US-2003/0108781	06-2003	Oh et al.	429/13
*	C	US-6,977,234	12-2005	Kosako et al.	502/101
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	J	US-			
	K	US-			
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	M	US-			

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**NON-PATENT DOCUMENTS**

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